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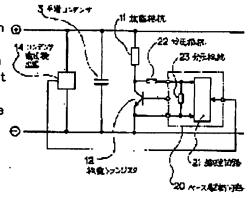
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## (54) OVERVOLTAGE INHIBITION CIRCUIT OF CAPACITOR

## (57) Abstract:

PROBLEM TO BE SOLVED: To easily detect the failure in the charge circuit of a capacitor without using any expensive DC voltage detectors or DC current transformers.

SOLUTION: In a conventional circuit where the series circuit of a discharge resistor 11 and a discharge transistor 13 is connected in parallel with a smoothing capacitor 3, and a capacitor voltage detector 14 gives an ON command to a base drive circuit 20 when a first setting voltage is exceeded and gives an OFF command to it when a second setting voltage cannot be exceeded, the presence or absence of the voltage between the collector and emitter of the discharge transistor 12 is detected by a voltage-dividing resistor 23, and the presence or absence of the voltage and the ON/OFF commands are given to a logic circuit 21. A logic circuit 21 judges to be abnormal and abnormal when the voltage of the voltage—dividing resistor 23 exists or is equal to zero, respectively, when the ON command is issued, and judges to be normal and abnormal when the voltage of the voltage—dividing resistor 23 exists and is equal to zero, respectively, when the OFF command is issued.



## **LEGAL STATUS**

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